



INTERNATIONAL ATOMIC ENERGY AGENCY
UNITED NATIONS EDUCATIONAL, SCIENTIFIC AND CULTURAL ORGANIZATION



INTERNATIONAL CENTRE FOR THEORETICAL PHYSICS
34100 TRIESTE (ITALY) - P.O.B. 550 - MIRAMARE - STRADA COSTIERA 11 - TELEPHONE: 2240-1
CABLE: CENTRATOM - TELEX 460592-1

SMR/384 - 6

**EXPERIMENTAL WORKSHOP ON
"HIGH TEMPERATURE SUPERCONDUCTORS"
(30 March - 14 April 1989)**

**INTRODUCTION TO EXPERIMENTAL ACTIVITY:
MATERIALS CHARACTERIZATION
(Parts I & II)**

Gunther LEISING
Solid State Physics Institute
Graz Technical University
Petersgasse 16
A-8010 Graz
Austria

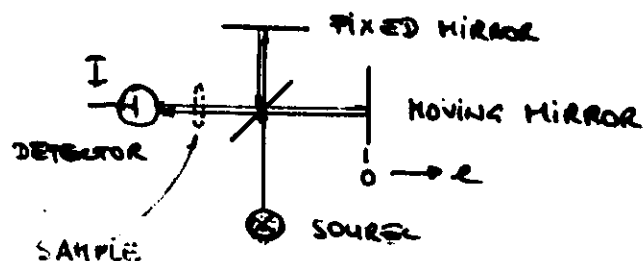
These are preliminary lecture notes, intended only for distribution to participants.

INFRARED SPECTROSCOPY

1

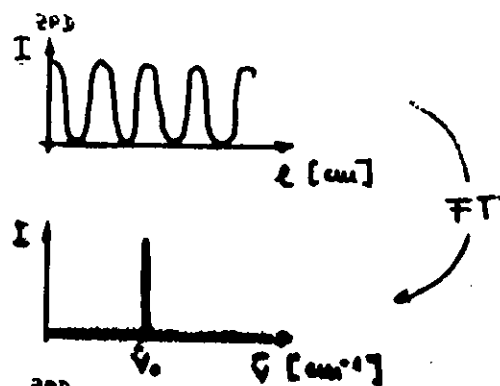
BASIC PRINCIPLE OF IR-SPECTROMETER

- DISPERSIVE
- FTIR

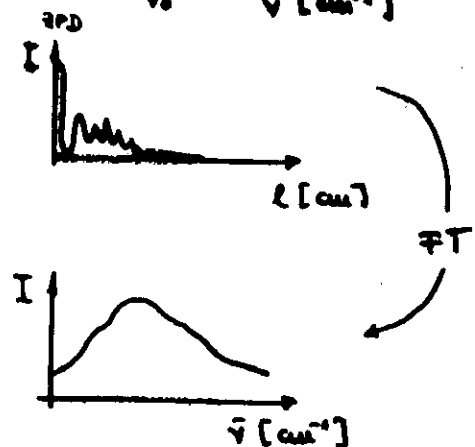


MICHELSON INTERFEROMETER

MONOCHROMATIC
LIGHT SOURCE



POLYCHROMATIC
LIGHT SOURCE



I-SAMPLE SPECTRUM IS TAKEN IMMEDIATELY AFTER
I₀-BACKGROUND SPECTRUM

$$\text{TRANSMISSION} = \frac{I(\bar{\nu})}{I_0(\bar{\nu})}$$

SINCE SINGLE BEAM MEASUREMENT
ABSORPTIONS FROM H₂O, CO₂

$$\text{CO}_2 : \nu_{\text{as}} = 2350 \text{ cm}^{-1}$$

$$\nu_{\text{sym}} = 666 \text{ cm}^{-1}$$

$$\text{H}_2\text{O} : \nu_{\text{sym}}, \nu_{\text{asym}} \sim 3700 \text{ cm}^{-1}$$

$$\nu_{\text{bend}} \sim 1500 \text{ cm}^{-1}$$

BROAD DISTRIBUTION OF NARROW
LINES $\Rightarrow$ ROTATIONAL SPLITTING

BELOW $\sim 400 \text{ cm}^{-1}$
PURE ROTATION BAND OF H₂O

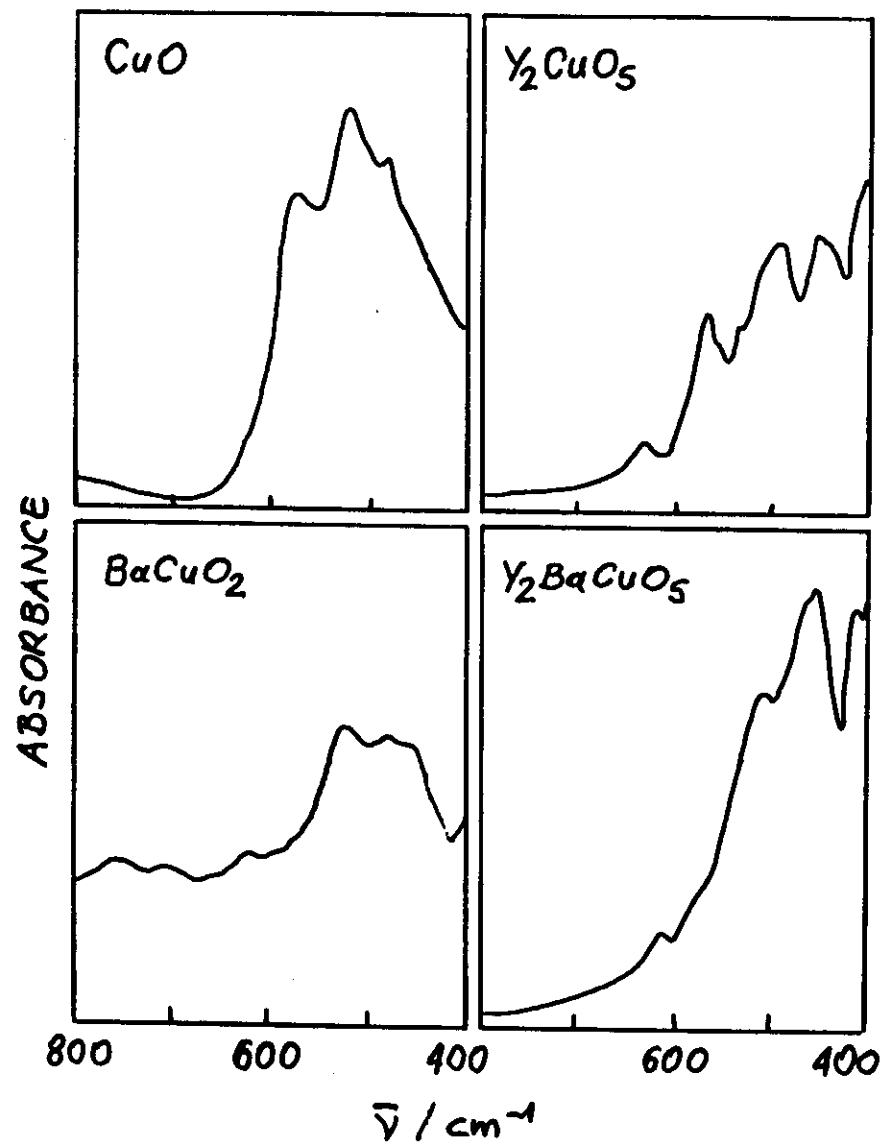
$\Rightarrow$ INSTRUMENT PURGED BY N₂ FLOW

PELLET MATERIALS FOR TRANSMISSION

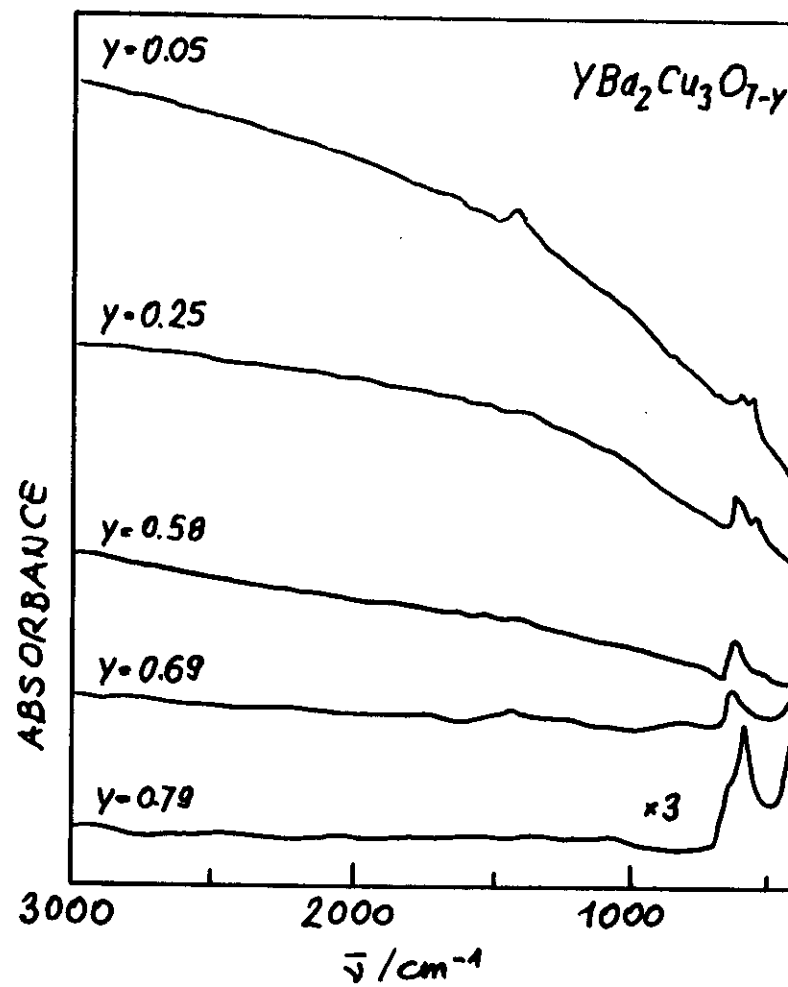
$$\text{KBr} \quad \nu_{\text{min}} \sim 400 \text{ cm}^{-1}$$

$$\text{CsI} \quad \nu_{\text{min}} \sim 200 \text{ cm}^{-1}$$

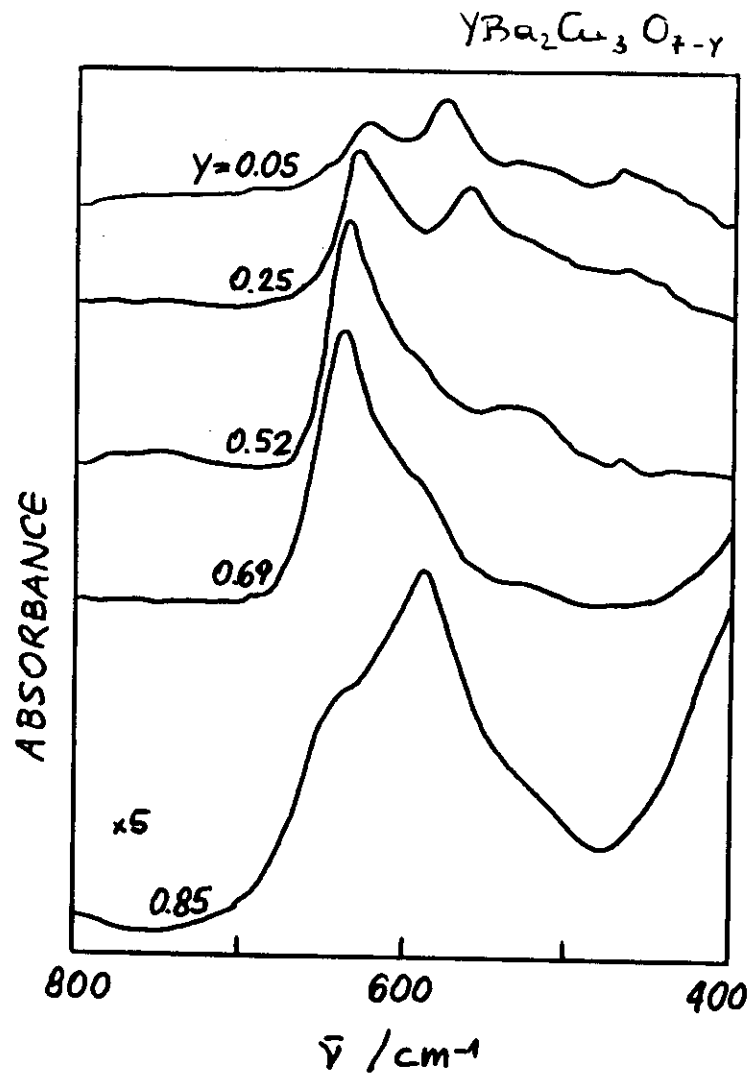
CAUTION: DIFFUSE SCATTERING IF NOT
CAREFULLY PREPARED



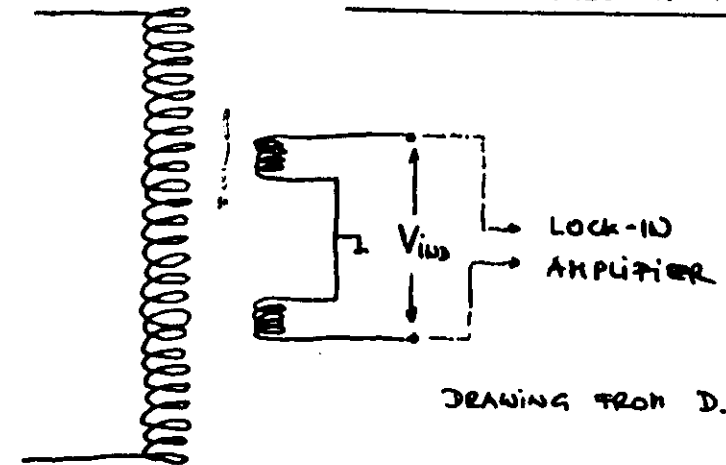
FROM C. TALIANI et al.



FROM C. TALIANI et al.



FROM: C. TALIANI et al.



DRAWING FROM D. DROZAC

AC - SUSCEPTIBILITY
SET UP

A_s : CROSS SECTIONAL
AREA OF THE
PICK-UP COIL
 N_s : NUMBER OF TURNS
 F : FILLING FACTOR

$$V_{ind} = - \frac{d\phi}{dt} \approx - \frac{d}{dt} [N_s A_s (\mu_0 H + \mu_0 F H) - N_s A_s / \mu_0 H]$$

$$= -\mu_0 \cdot N_s \cdot F \cdot A_s \frac{dH}{dt} = -\mu_0 \cdot N_s \cdot F \cdot A_s \frac{dH}{dH} \cdot \frac{dH}{dt}$$

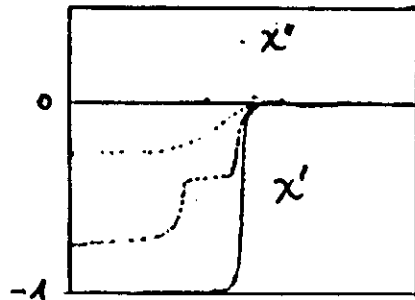
$$H = H_0 \cdot e^{i\omega t}$$

$$V_{ind} = -i \mu_0 \cdot \omega \cdot H \cdot N_s \cdot F \cdot A_s \cdot \frac{dH}{dH}$$

$$V_{ind} \sim \chi$$

$$\chi = \chi' + i\chi''$$

LOCK-IN TECHNIQUE: BY DETECTING THE INPHASE AND OUT-OF PHASE COMPONENT $\Rightarrow$ GIVING THE REAL PART AND IMAGINARY PART OF χ



-1: CORRESPONDS TO A COMPLETE FIELD EXPULSION
PERFECT DIAMAGNETISM

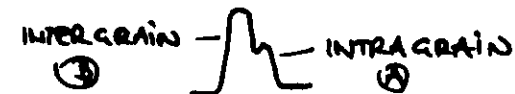
FOR ABSOLUTE MEASUREMENT, CALIBRATION TO
A KNOWN REFERENCE HAS TO BE DONE.

OTHER FACTORS: SAMPLE DENSITY, POROSITY
ABSOLUTE FILLING FACTOR, SAMPLE GEOMETRY

INFORMATION:

- PERCENTAGE OF SUPERCONDUCTING VOLUME
- DISTRIBUTION OF SUPERCONDUCTING TRANSITION TEMPERATURES
- DETECT SUPERCONDUCTING PHASES OF LOW PERCENTAGE (NOT SEEN IN RESISTIVITY)
 $\Rightarrow$ CAUTION: PHASE TRANSITIONS
- SEPARATING INTERGRAIN AND INTRAGRAIN CONTRIBUTIONS

GOOD SAMPLE OF $\text{YBa}_2\text{Cu}_3\text{O}_7$ SHOWS
TWO PEAKS IN $\chi''(T)$



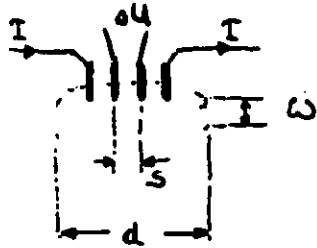
WHERE ② DEPENDS MORE STRONGLY ON
THE APPLIED FIELD (H_c , J_c) THAN ①

IN AVERAGE QUALITY SAMPLES ONLY
② IS SEEN

TRANSPORT PROPERTIES

ELECTRICAL RESISTIVITY:

CONVENTIONAL 4-PROBE ARRANGEMENT
FOR CHARACTERIZING CERAMIC SAMPLES



IF $s \ll w, d$

$$\Rightarrow \rho = 2\pi s \cdot \frac{U}{I}$$

IF $s \ll w, d$ DOES NOT HOLD $\Rightarrow$

CORRECTIONS

w/s	K
0.4	0.9995
0.7	0.9798

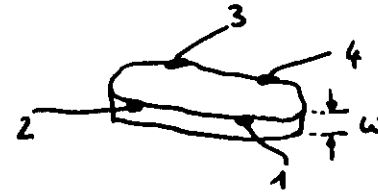
THE CORRECTIONS IN CASE OF d ARE MORE
DIFFICULT TO TAKE INTO ACCOUNT

BUT

WITH OUR CONTACT ARRANGEMENT AND SAMPLE
SIZE WE CAN HOLD $s \ll d$.

9

VAN DER PAUW - GEOMETRY



$$R_1 = U_{34} / I_{12}$$

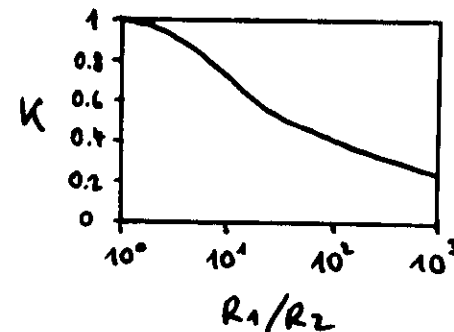
$$R_2 = U_{14} / I_{23}$$

- HOMOGENEOUS SAMPLE AND THICKNESS
- NO HOLES

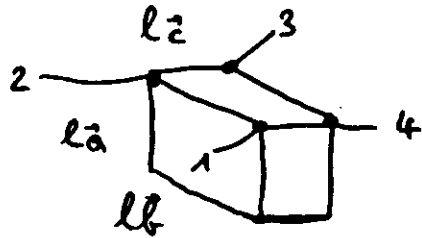
THEN

$$\rho = \frac{T \cdot w}{\ln 2} \cdot \frac{R_1 + R_2}{2} \cdot K$$

CORRECTION FACTOR FOR RESISTIVITY RATIOS:



ANISOTROPIC SAMPLES, SINGLE CRYSTALS
FOR THE DETERMINATION OF THE CONDUCTIVITY
TENSOR



CONTACTS WITH
SILVER PAINT
→ ANNEALED IN O_2 /
 $400^\circ C$

VAN DER PAUL ARRANGEMENT

l_a, l_b, l_c HAVE TO BE MEASURED ACCURATELY

CONTACTS NOT TOO LARGE !

$$R_c = U_{14} / I_{23}$$

$$R_b = U_{12} / I_{34}$$

WITH R_c, R_b, l_a, l_b, l_c IN GRAPHS OF

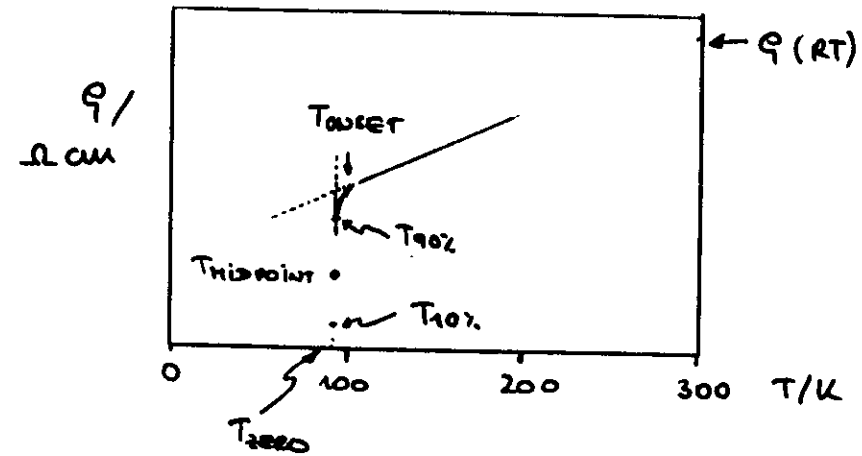
REF: H.C. MONTGOMERY

J. APPL. PHYS. 42 (1971) 2971



ρ_a, ρ_b

CHARACTERIZATION OF RESISTIVITY BEHAVIOUR



DESIRED VALUES :

RESISTIVITY AT ROOM TEMPERATURE

$$\rho_{RT} < 1 \text{ m}\Omega\text{cm}$$

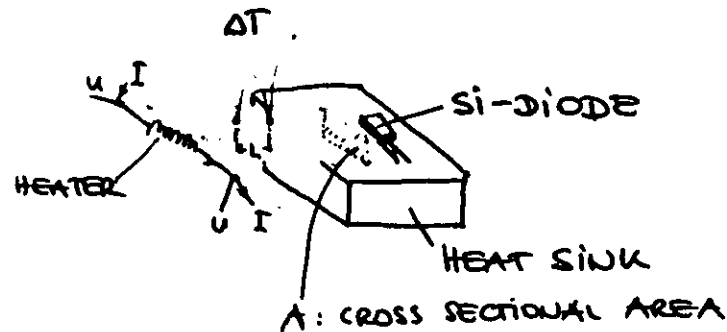
RESISTIVITY RATIO BETWEEN RT AND $T_{0.5\%}$

$$\rho(RT) / \rho(T_{0.5\%}) \geq 3$$

WIDTH OF THE TRANSITION

$$T_{90\%} - T_{10\%} = \Delta T \leq 1 \text{ K}$$

THERMAL CONDUCTIVITY (STEADY-STATE METHOD)



P : FOUR PROBES MEASUREMENT TO ACCOUNT FOR RESISTIVITY CHANGES OF HEATER

$$P = U \cdot I$$

$$\Rightarrow K = \frac{P}{\Delta T} \cdot \frac{L}{A} \quad \text{W cm}^{-1} \text{K}^{-1}$$

FOR POOR THERMAL CONDUCTORS: POSSIBLE ERRORS WITH MEASUREMENTS AT HIGH TEMPERATURES ($> 200\text{K}$) DUE TO RADIATION LOSSES

INFORMATION FROM THERMAL CONDUCTIVITY

- CONTRIBUTION OF CHARGE CARRIERS
- " " OF PHONONS
- " " OF ELECTRON-PHONON INTERACTION

$$K = K_{\text{CARRIERS}} + K_{\text{PHONONS}}$$

ASSUMING ELASTIC SCATTERING OF CARRIERS

ESTIMATE OF K_{CARRIERS} FROM THE

WIEDEHANN-TRANZ LAW

$$K_{\text{CARRIERS}} = \frac{1}{9} L_0 \cdot T$$

$$L_0 = 2.45 \cdot 10^{-8} \text{ W } \Omega \text{ K}^{-1} \quad \text{LORENZ NUMBER}$$

IF SIGNIFICANT INELASTIC SCATTERING

$$L_{\text{EFFECTIVE}} < L_0$$

UPPER LIMIT FOR K_{CARRIERS}

$$K_c(100\text{K}) < 2.5 \cdot 10^{-4} \text{ W cm}^{-1} \text{K}^{-1} \quad (\rho(100\text{K}) = 10 \text{ m}\Omega \text{ cm})^*$$

$$K_c(100\text{K}) < 2.5 \cdot 10^{-2} \text{ W cm}^{-1} \text{K}^{-1} \quad (\rho(100\text{K}) = 100 \mu\Omega \text{ cm})$$

* FROM: MORELLI et al Phys. Rev. B 36 (1987) 3917

THERMOPOWER - SEEBECK COEFFICIENT, $S(T)$

THE SAME EXPERIMENTAL ARRANGEMENT AS FOR THERMAL CONDUCTIVITY

INFORMATION:

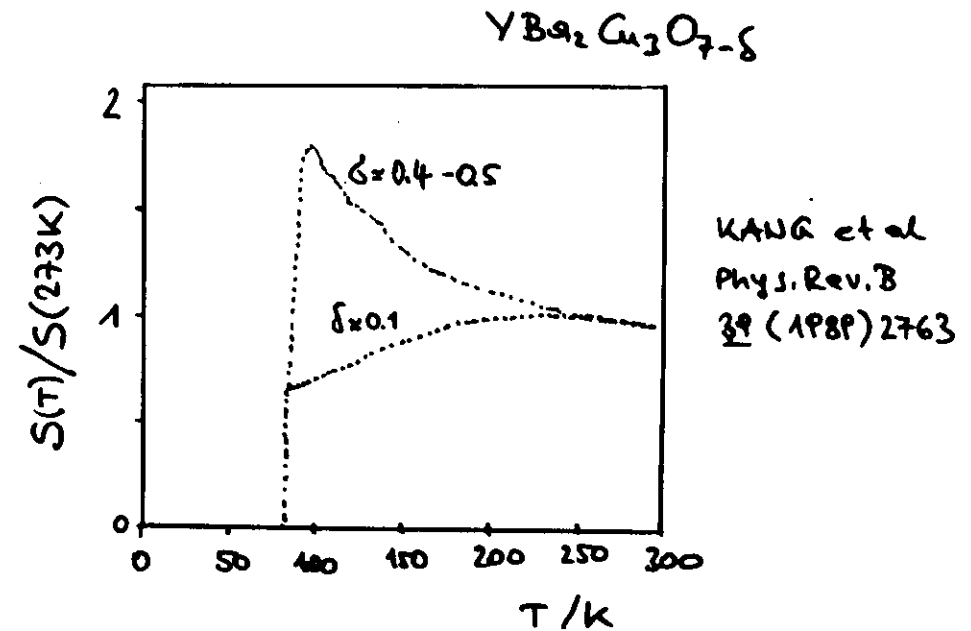
- SIGN OF MAJORITY CARRIERS
- VALUE OF S : • BETWEEN $100 - 1000 \mu\text{V/K}$ FOR SEMICONDUCTORS
 - LESS THAN $100 \mu\text{V/K}$ DOWN TO A FEW $\mu\text{V/K}$ FOR METALS
 - ZERO IN THE SUPER-CONDUCTING STATE
- CARRIER SCATTERING ON CARRIERS AND PHONONS

SIMPLE MODEL ASSUMING NEARLY FILLED BAND METALLIC SYSTEM AND ENERGY INDEPENDENT SCATTERING

$$S(T) = \frac{T^2}{3} \cdot \frac{k_B}{e} \cdot T \cdot \eta(E_F)$$

$\eta(E_F)$: DENSITY OF STATES PER CARRIER AT THE FERMIL LEVEL

OBSERVED BEHAVIOUR:



MORE REALISTIC:

ENERGY DEPENDENT SCATTERING

$$S(T) = \frac{T^2 k_B}{3e} \cdot T \cdot \frac{d \ln \sigma(E)}{d E_F}$$

THERMOGRAVIMETRY



IF ALL Cu IS IN Cu^{2+} OR $(\text{CuO})^0$



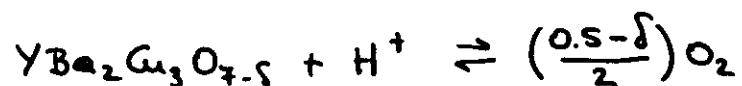
IF $\delta < 0.5$

THEN SOME $(\text{Cu-O})^+ = 2(0.5 - \delta)$

THIS CAN BE EVALUATED BY

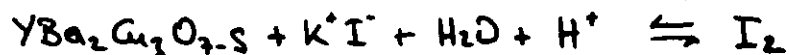
- O_2 EVOLUTION
- IODOMETRY
- TGA

O_2 -EVOLUTION:



EVOLVED O_2 MEASURED

IODOMETRY:



I_2 AMOUNT DETERMINED BY TITRATION
WITH $\text{Na}_2\text{S}_2\text{O}_3$

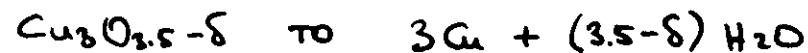
TGA:



↑

THIS SPECIES CANNOT BE
FURTHER REDUCED

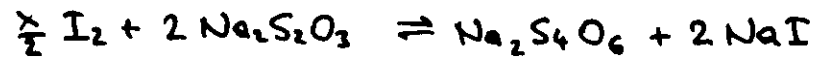
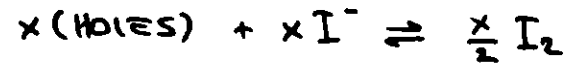
DOING TGA UNDER H_2 ATMOSPHERE
WILL REDUCE



FROM WEIGHT LOSS $\Rightarrow \delta$

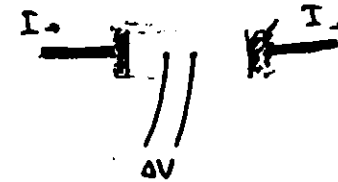
AND CHECKING WITH IODOMETRIC RESULT

PRINCIPLE - IODOMETRY



CRITICAL CURRENT

ARRANGEMENT:

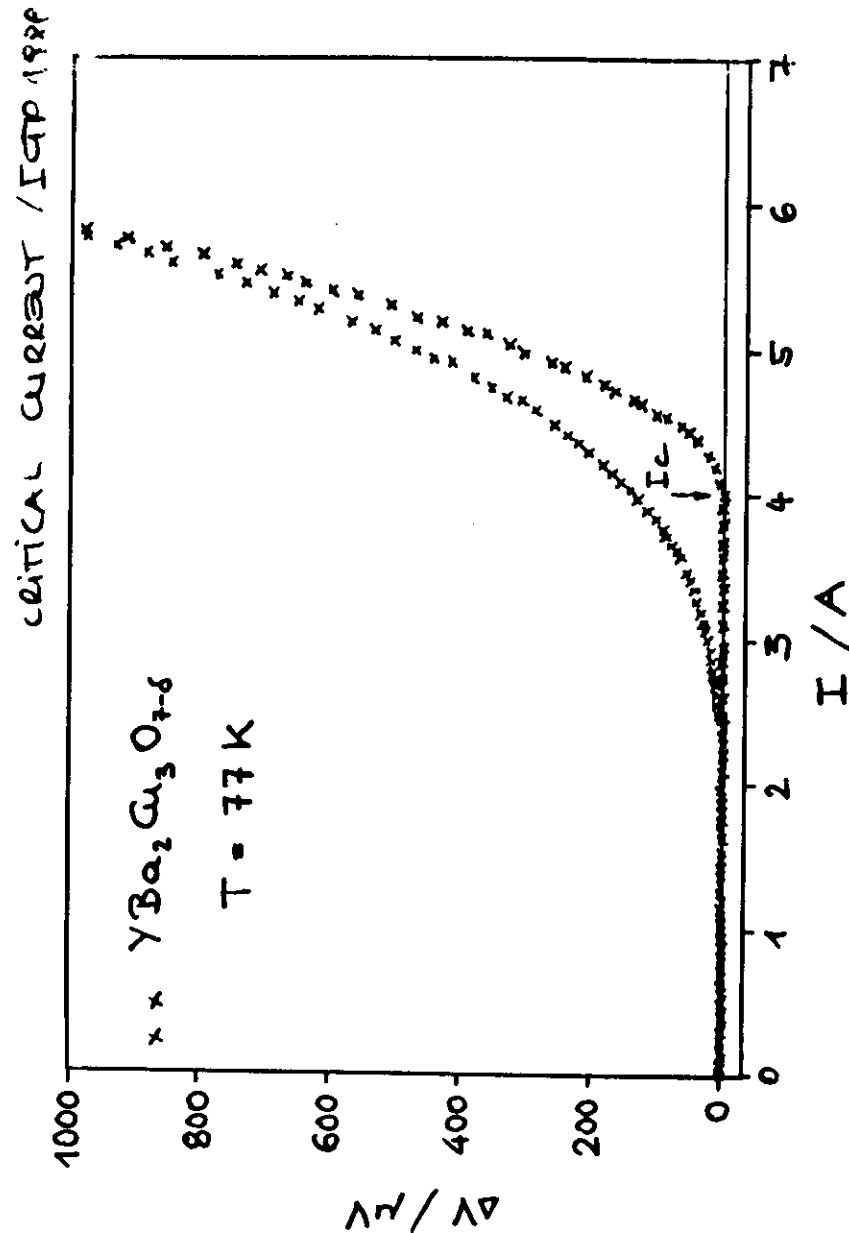


- IMPORTANT • GOOD THERMAL CONTACT OF SAMPLE TO THE HEAT SINK $\Rightarrow$ THEREFORE SAMPLE IMMERSED IN LIQUID NITROGEN FOR GOOD THERMAL CONTACT
- VERY GOOD CURRENT CONTACTS (LOW CONTACT RESISTANCE)
POSSIBLE CONTACT MATERIALS FOR $\text{YBa}_2\text{Cu}_3\text{O}_{7-x}$ - IN SOLDERED TO SAMPLE OR AG PASTE CONTACTS ANNEALED UNDER O_2 / 400°C FOR SEVERAL HOURS.

MEASUREMENT: COMPUTER CONTROLLED
SWEEPS AUTOMATICALLY THE CURRENT

FIT TO $\Delta V = A_0 \exp(I - I_c)$

BASIC IDEA: PERCOLATION PROCESS INVOLVED FOR DESCRIBING THE DISTRIBUTION OF NORMAL DRIVEN WEAK LINKS.



CRITICAL CURRENT VALUES : $J_c (\text{YBa}_2\text{Cu}_3\text{O}_{7-d})$

INTRAGRAIN $\geq 10^6 \text{ A/cm}^2$

INTERGRAIN $\sim 200 \text{ A/cm}^2$

⇒ CRITICAL CURRENT VALUES OF CERAMICS ARE DETERMINED BY THE INTERGRAIN J_c

SOME POSSIBLE REASONS FOR THE OCCURRENCE OF THE WEAK LINK JUNCTIONS AT THE GRAIN BOUNDARIES :

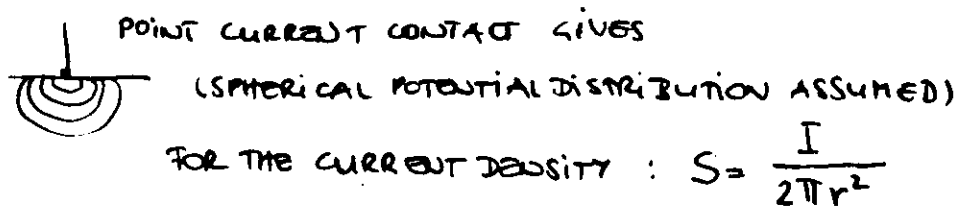
- THE SMALL COHERENCE LENGTH ($\sim 10 \text{ \AA}$)
- MISALIGNMENT OF NEIGHBOURING GRAINS (LARGE ANISOTROPY OF SC PROPERTIES)
- DISTURBANCE OF THE STRUCTURE AT THE GRAIN BOUNDARY
- FOREIGN PHASES OR JUNK IN THE GRAIN BOUNDARY

CONCLUSION: J_c MEASUREMENT IS A TEST FOR THE INTERGRAIN CONTACT SO FOR THE QUALITY OF THE SAMPLE.

IDEAS : GRAIN BOUNDARY JOINER

APPLICATIONS

4-PROBE RESISTIVITY IN LINE CONTACTS



WITH OHM'S LAW : $\vec{S} \cdot \vec{\rho} = \vec{E}$ IT GIVES $\Rightarrow$

$$E = \frac{I}{2\pi r^2} \rho$$

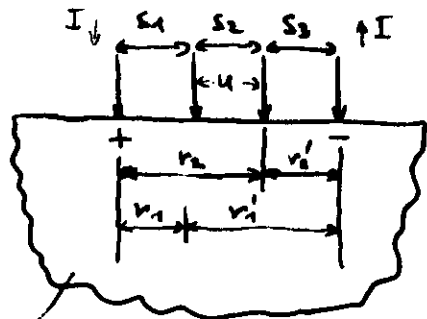
THE POTENTIAL DIFFERENCE BETWEEN TWO POINTS

$$U = - \int_{r_1}^{r_2} E dr = - \frac{I}{2\pi} \rho \int_{r_1}^{r_2} \frac{1}{r^2} dr = \frac{I}{2\pi} \rho \left(\frac{1}{r_1} - \frac{1}{r_2} \right)$$

THE APPROXIMATION FOR EXAMPLE r_2 WITH $r_2 \rightarrow \infty$

$\Rightarrow$ POTENTIAL $\rho = \frac{I}{2\pi} \rho \frac{1}{r}$

WITH THE ARRANGEMENT :



$$\rho_1 = \frac{I}{2\pi} \rho \left(\frac{1}{r_1} - \frac{1}{r_1'} \right)$$

$$\rho_2 = \frac{I}{2\pi} \rho \left(\frac{1}{r_2} - \frac{1}{r_2'} \right)$$

CRYSTAL

$$U = \rho_1 - \rho_2 = \frac{I}{2\pi} \rho \left(\frac{1}{r_1} - \frac{1}{r_1'} - \frac{1}{r_2} + \frac{1}{r_2'} \right)$$

EXPRESSING r_i BY $S \Rightarrow$

$$U = \frac{I}{2\pi} \rho \left(\frac{1}{s_1} - \frac{1}{s_2+s_3} - \frac{1}{s_1+s_2} + \frac{1}{s_3} \right)$$

FOR EQUAL CONTACT DISTANCES

$$s_1 = s_2 = s_3 = S$$

$$\Rightarrow \boxed{\rho = 2\pi S \frac{U}{I}}$$

WE DID NOT TAKE INTO ACCOUNT THE SAMPLE BOUNDARY SO THE ABOVE IS ONLY VALID FOR $d \gg S$ AND $w \gg S$

